

High granularity timing detector (HGTD) activity at IHEP/NJU

梁志均（中国科学院高能物理研究所）

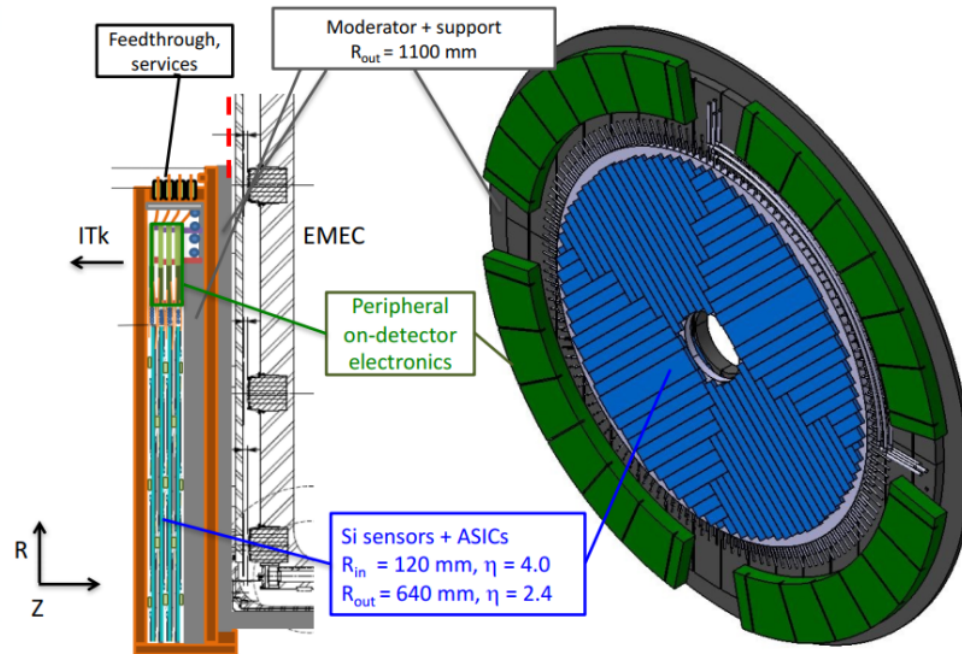
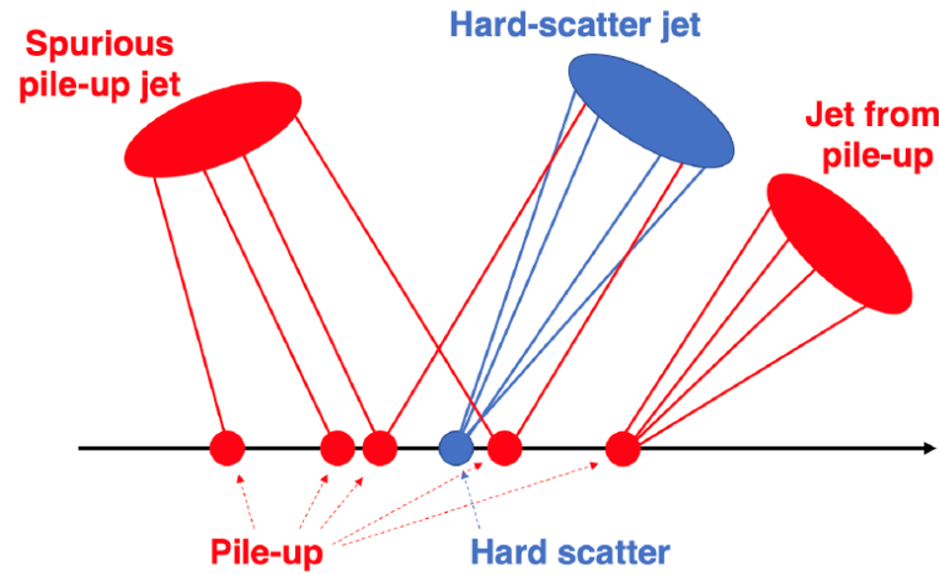
Zhijun Liang（IHEP,CAS）

On behalf of IHEP/NJU HGTD team

The 6th CLHCP workshop, 6 -9 Nov 2020, Zoom

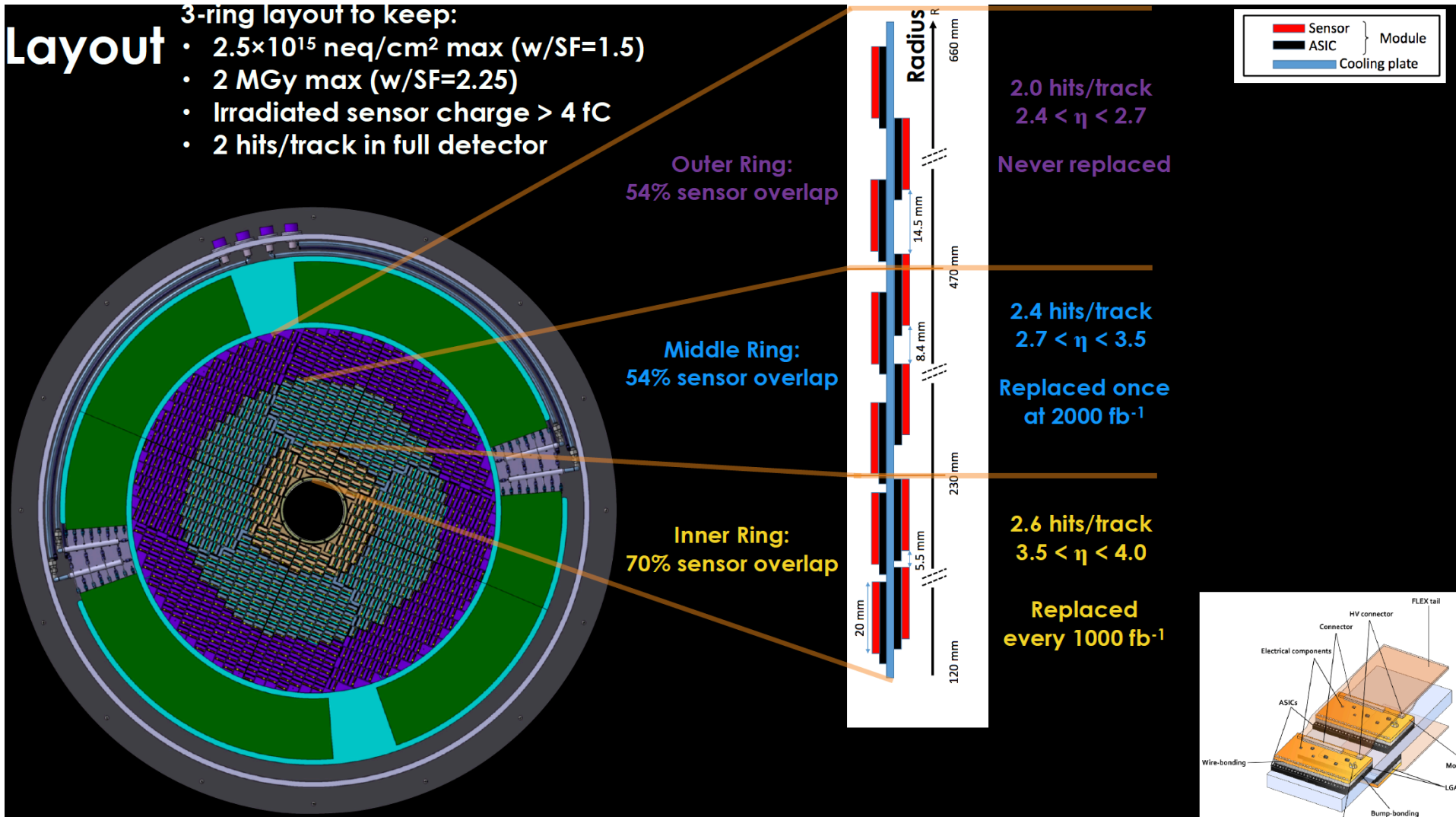
High-Granularity Timing Detector (HGTD)

- HGTD approved by CERN Research Board on Sep 2020
- HGTD aim to reduce pileup contribution at HL-LHC
 - Timing resolution is required to be better than **50ps**
 - **6.4m² area** silicon detector and **~ 5x10⁶** channels
 - Radiation hardness: **2.5x10¹⁵ N_{eq}/cm²** and **2MGy**



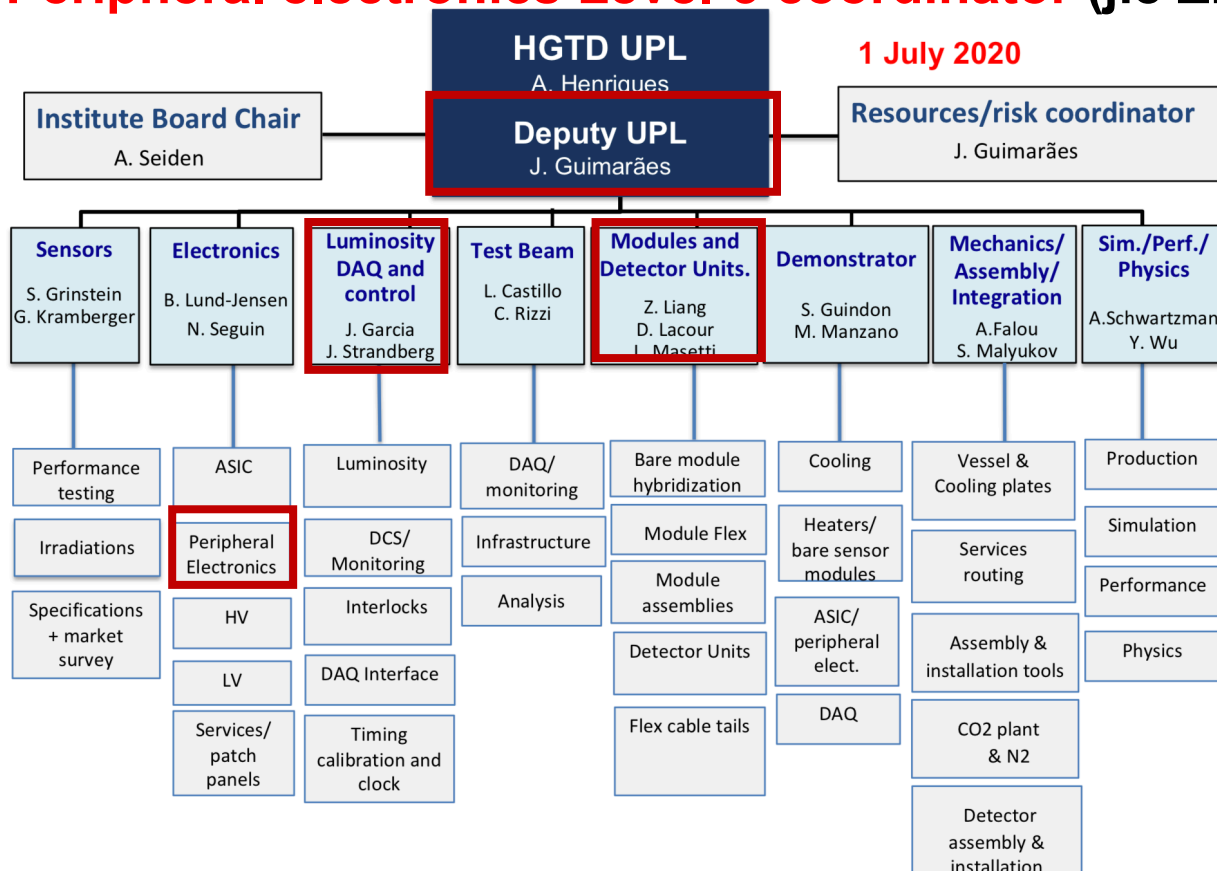
HGTD: layout and irradiation hardness

➤ 3-rings layout, two double layer of silicon detectors (6.4m^2)



IHEP/NJU team in HGTD

- IHEP/NJU team (~15 faculty, ~10 postdoc, 10+ students)
- Takes Leading roles in ATLAS HGTD project
 - HGTD deputy project leader (Joao Guimaraes Da Costa, IHEP)
 - Module group Level-2 coordinator (Zhijun Liang, IHEP)
 - DAQ Level-2 coordinator (Juanan Garcia, IHEP)
 - Peripheral electronics Level-3 coordinator (jie Zhang, IHEP)



Ultra-fast silicon sensor R & D

- Low gain avalanche diode(LGAD) is developed for HGTD
 - Radiation hard, **Medium gain**, High S/B, **fast timing**, **no self-triggering**

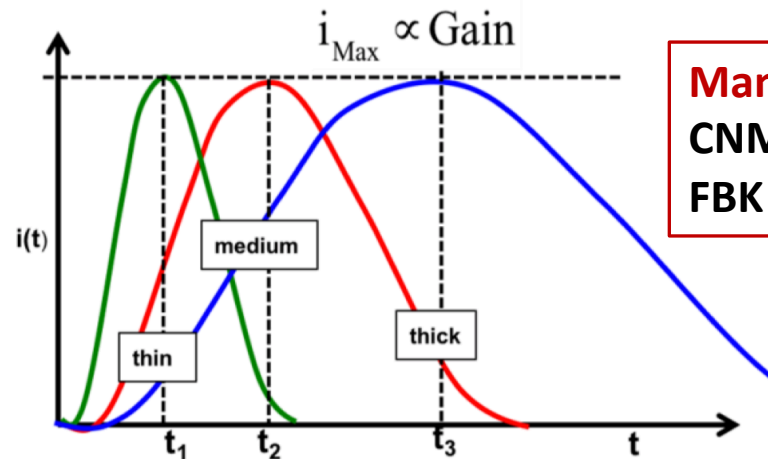
$$\sigma_t^2 = \sigma_{TimeWalk}^2 + \sigma_{LandauNoise}^2 + \sigma_{Distortion}^2 + \sigma_{Jitter}^2 + \sigma_{TDC}^2$$

- **Landau Noise term**

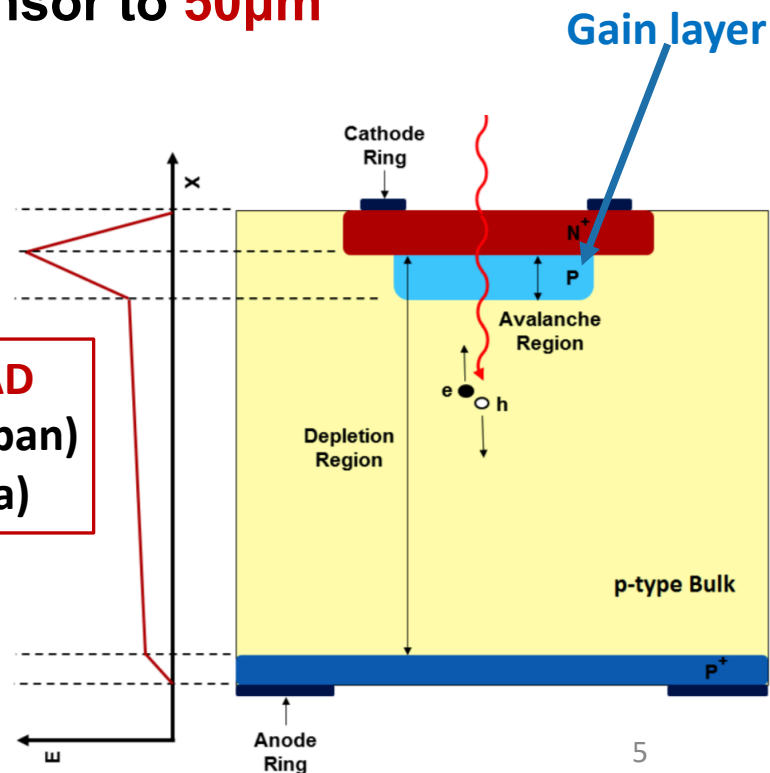
- Signal fluctuation due to non-uniform charge deposition
- Minimized by reducing thickness of sensor to **50 μ m**

- **Jitter term**

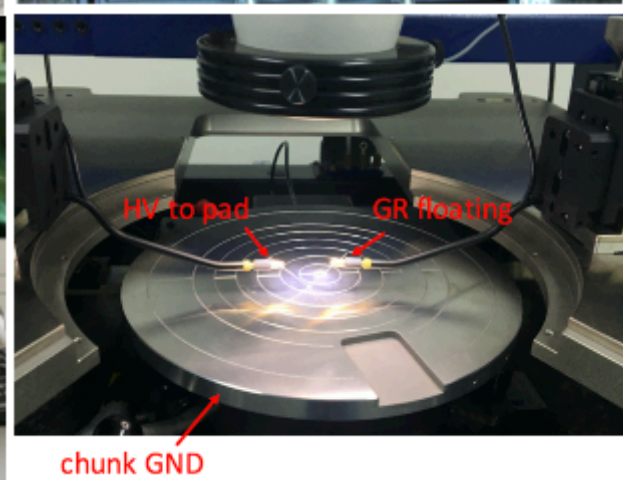
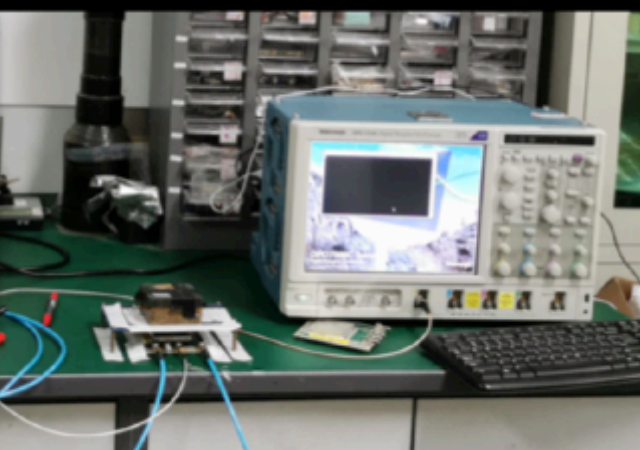
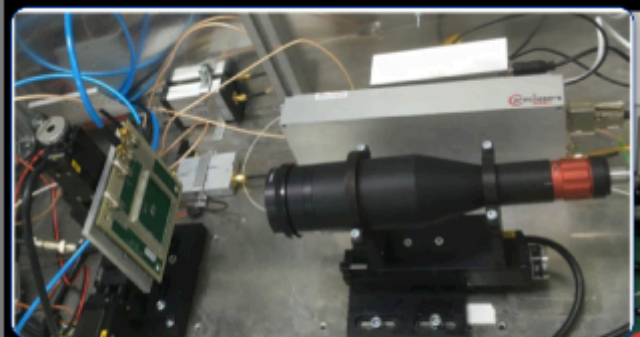
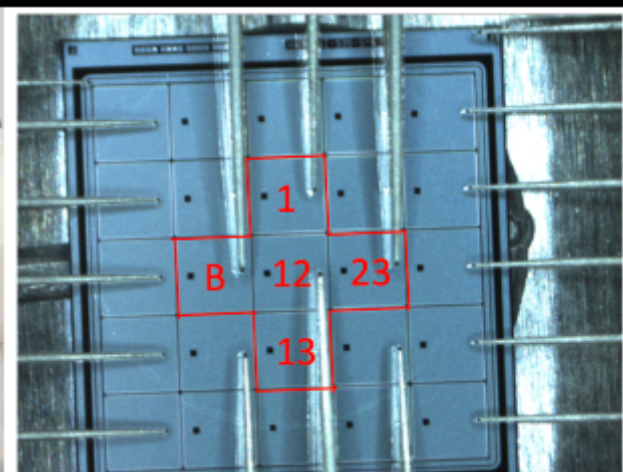
- Need **gain layer** to increase S/N
- Thin detector to decrease rise time



Manufacturers of LGAD
CNM (Spain), HPK (Japan)
FBK (Italy), NDL (China)



Sensors testing at IHEP



Ultra-fast silicon sensor R & D in IHEP

IHEP & Beijing Normal U. developed IHEP-NDL sensor

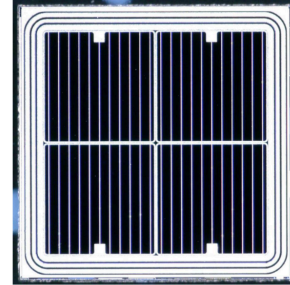
➤ Time resolution reached **30 pico-second (ps)**

IHEP-NDL sensor

➤ Collected charge is **>30fC** before irradiation

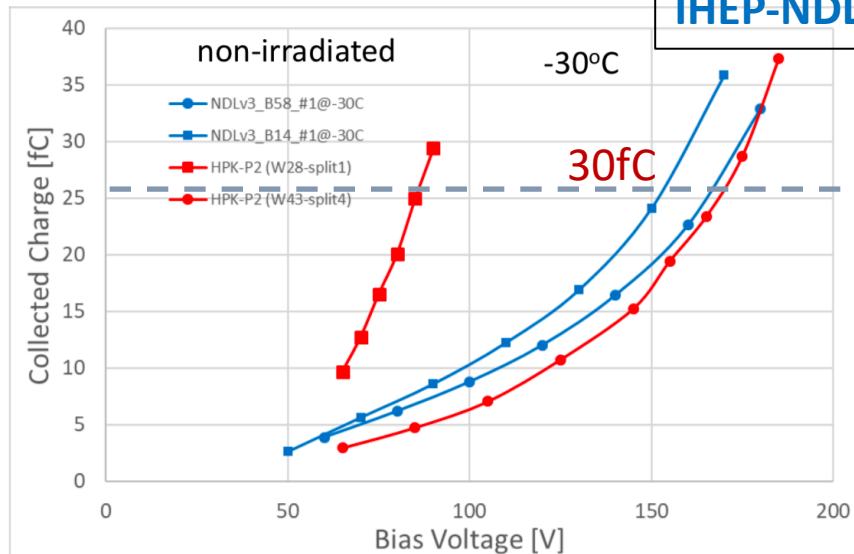
➤ ATLAS requirement is **>15fC**

➤ Performance close to Hamamatsu LGAD before irradiation

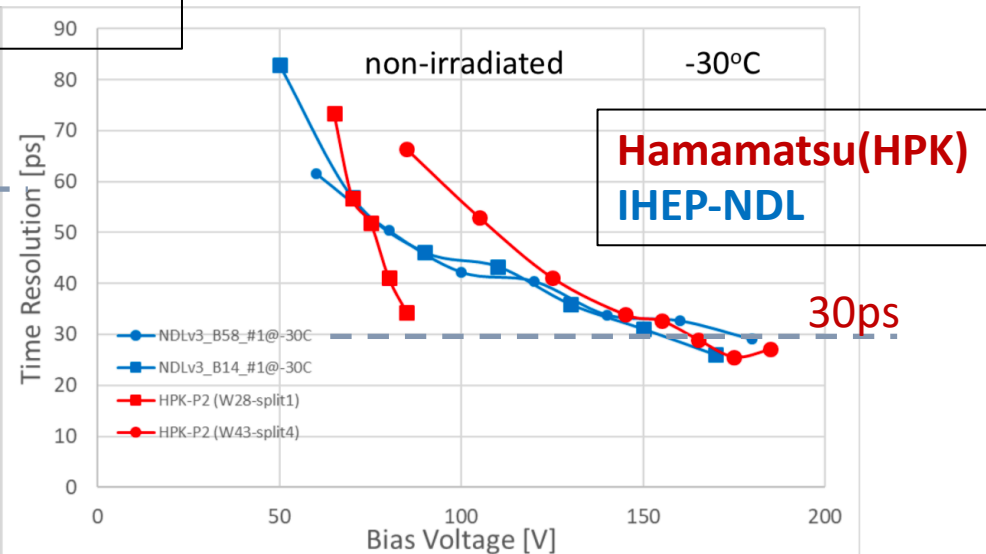


IHEP-NDL performance Verified by Ljubljana group

Time resolution in beta tests before irradiation



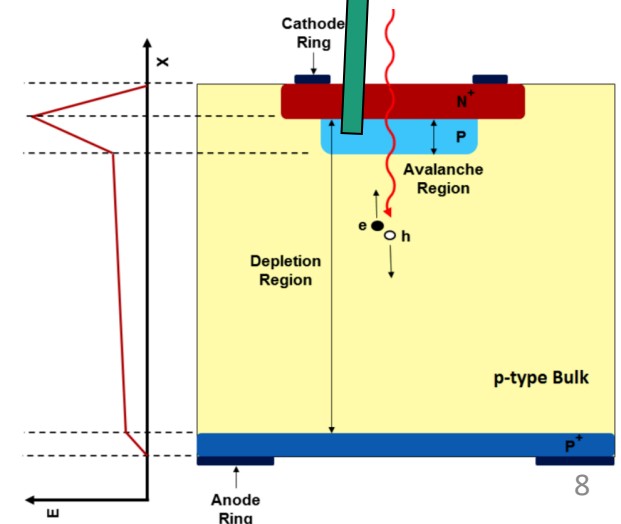
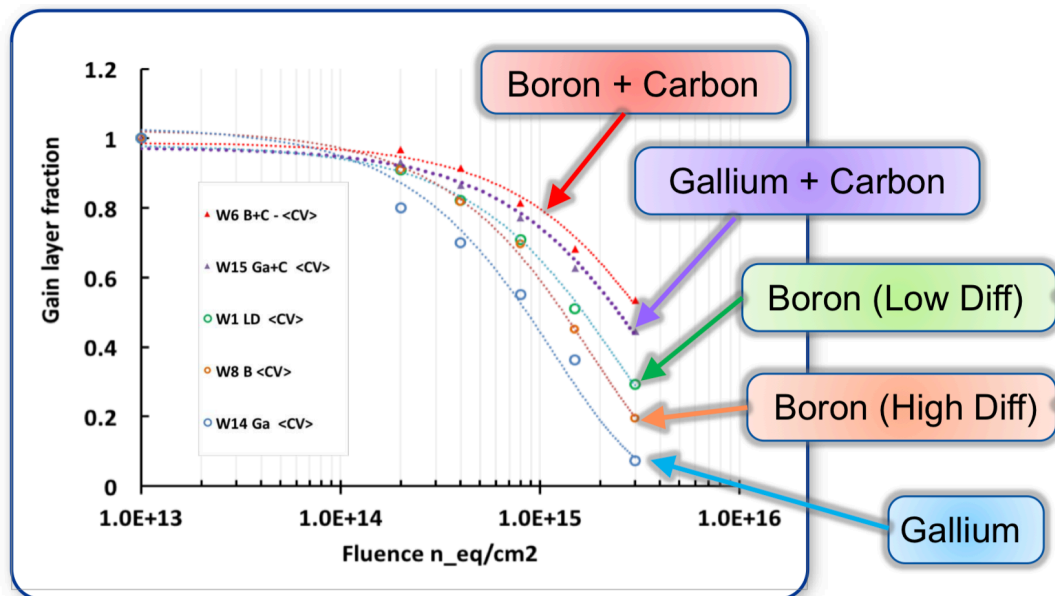
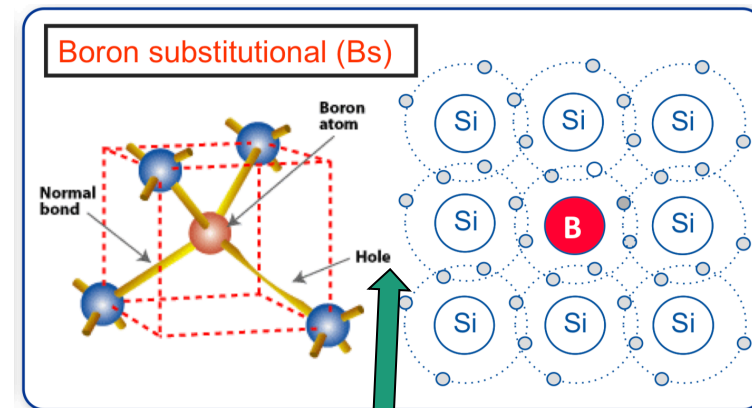
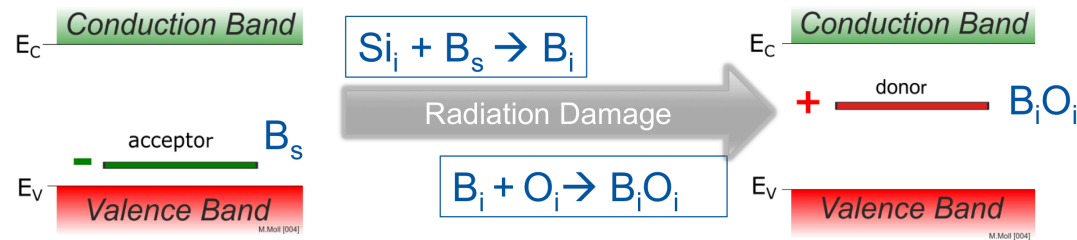
Collected charge in beta test before irradiation



Ultra-fast silicon sensor: irradiation hardness

➤ HGTD irradiation hardness requirement

- Total ionization does (TID) $\geq 200\text{MRad}$
- Fluence $\geq 2.5 \cdot 10^{15} \text{N}_{\text{eq}}/\text{cm}^2$
- Sensors suffered from acceptor removal effect (removing gain layer)



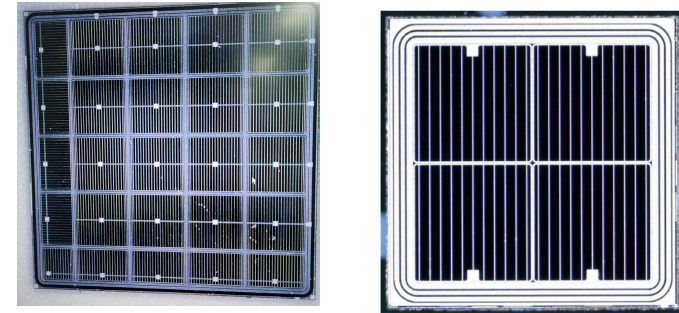
Ultra-fast silicon sensor : IHEP-NDL sensors

➤ Preliminary results of irradiated IHEP-NDL LGAD

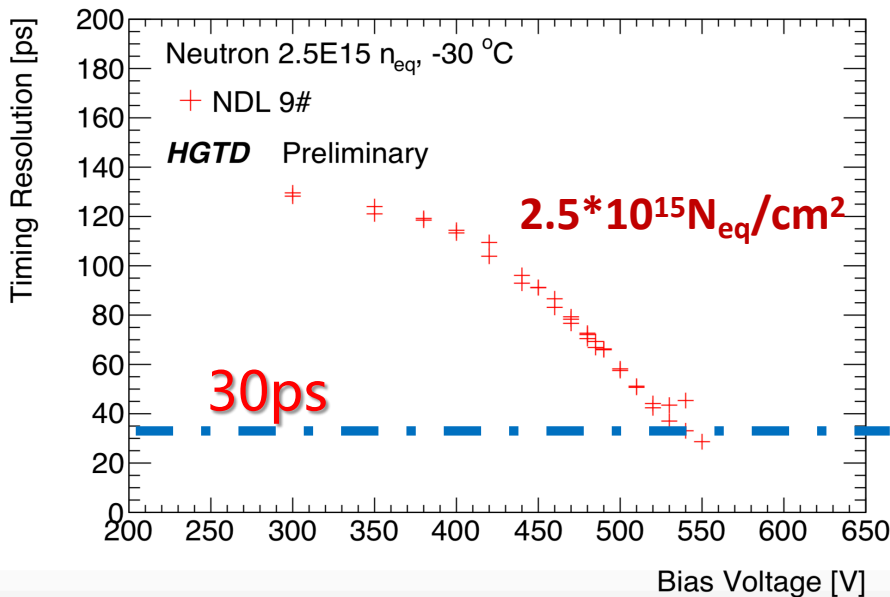
- Time resolution reached **30ps** at high fluence $2.5 \cdot 10^{15} N_{eq}/cm^2$
- Collected charge is **~4fC** after irradiation (**4fC** is ATLAS requirement)

➤ Next step (2021):

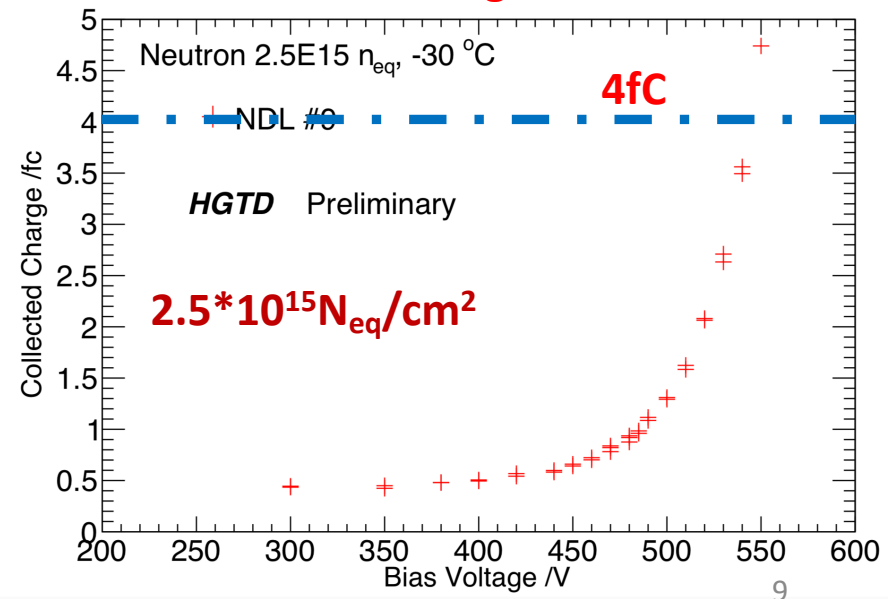
- Improve irradiation hardness
- Develop full size (4*2cm) sensors
- Compete with **HPK/FBK** in market survey



Time resolution after irradiation



Collected charge after irradiation

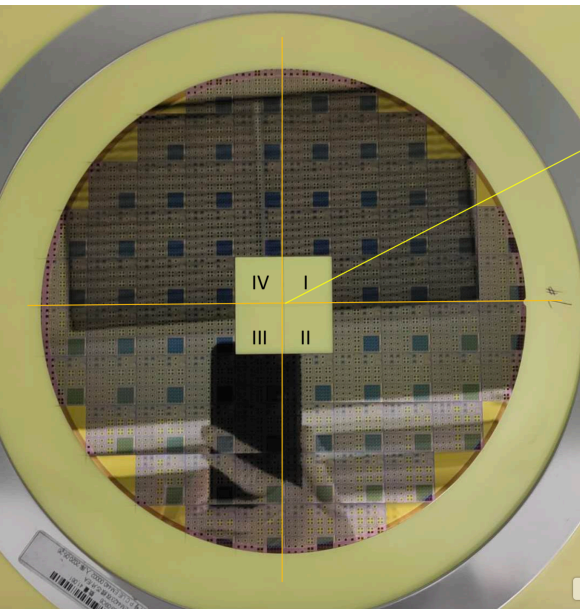


Ultra-fast silicon sensor: IHEP-IME sensors

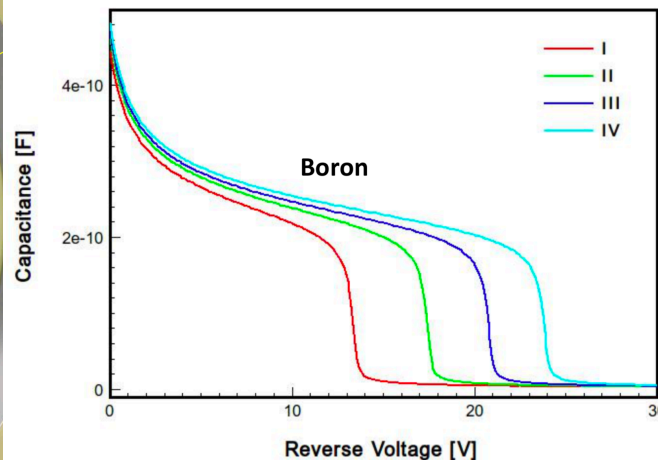
- IHEP & Institute of micro-electronics (IME) LGAD sensor
 - IHEP team designed, IME fabricated 1st prototype this September.
 - Depletion voltage are similar to designed value (4 doping design)
 - Good time resolution (**30-40ps**) and high charge collection (**20-30 fC**)
 - Next step:
 - Irradiation hardness study
 - Design full size sensor

See more in Kewei Wu's talk later at detector parallel session

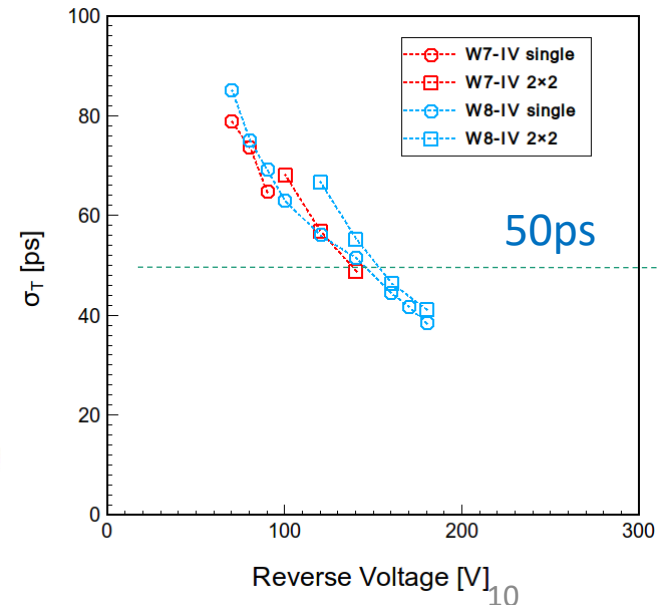
IHEP-IME sensors



Capacitance vs voltage
(4 doping design)



Time resolution before irradiation



50ps

Fast readout ASIC

➤ Feature of HGTD readout ASIC

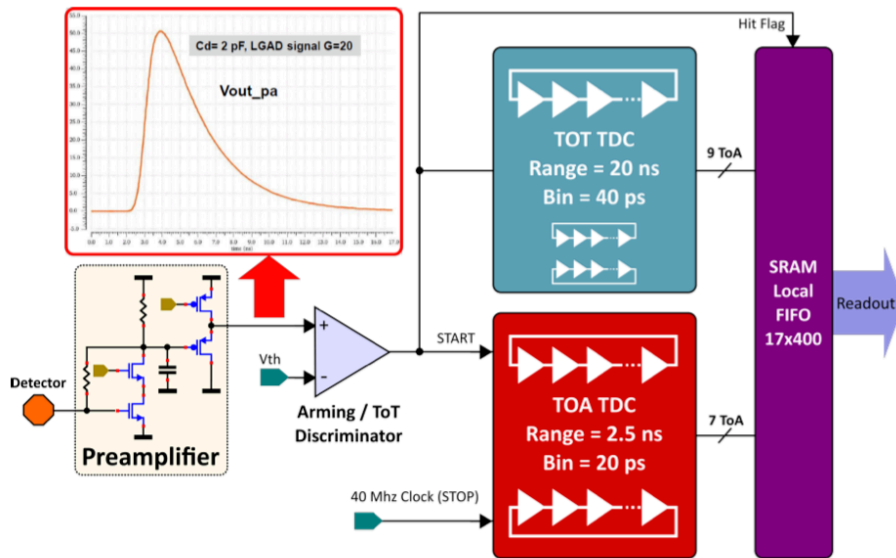
- Ultra-Fast readout chip (**10ps**), Radiation hardness (**200Mrad**)
- Use TDC for Time of Arrival (TOA) and Time Over Threshold (TOT)
- Status: small prototype (ALTIROC1) testing, full-size ASIC in 2021

➤ IHEP/NJU developed full-size ASIC emulator

- Beginning communication studies with FELIX DAQ system

➤ IHEP contributed to irradiation study of ALTIROC1_v3

Schematic of ASIC (ALTIROC)



ASIC emulator (IHEP/NJU)



X ray machine in IHEP For ASIC irradiation study

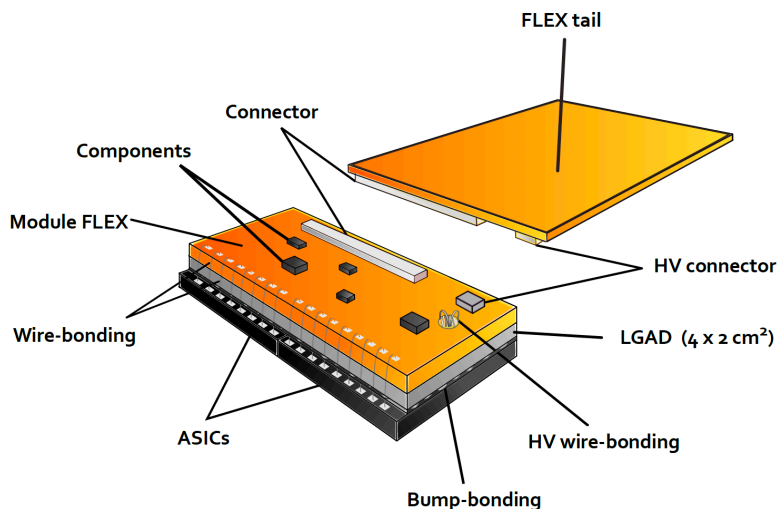


HGTD Module R& D

➤ IHEP is playing a leading role in module R& D

➤ IHEP performed 2 round of prototyping of mini-modules ($6.5 \times 6.5 \text{mm}^2$)

➤ Timing resolution at module level $\sim 40 \text{ps}$



~ 8000 module, $4 \times 2 \text{cm}^2$

2 ALTIROC ASiCs

Bump bonded to

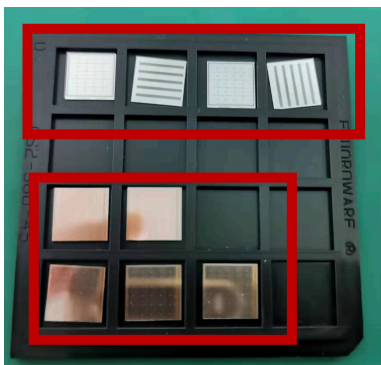
1 LGAD sensor

Wire bonded to Flex cable

15 x 30 channels

$1.3 \times 1.3 \text{mm}^2$ granularity

LGAD sensors



ALTIROC1 ASIC

Bare module (sensor+ASIC)

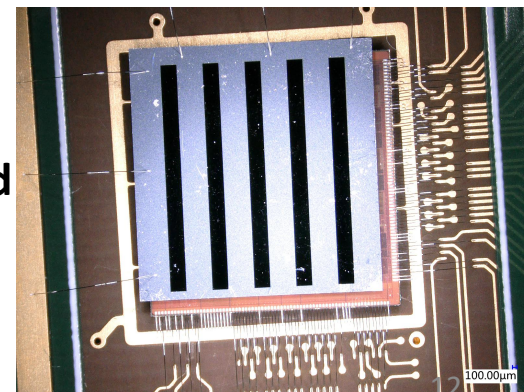
Bump bonding



**Wire Bonding
On test board**



Mini-modules



HGTD Module R&D

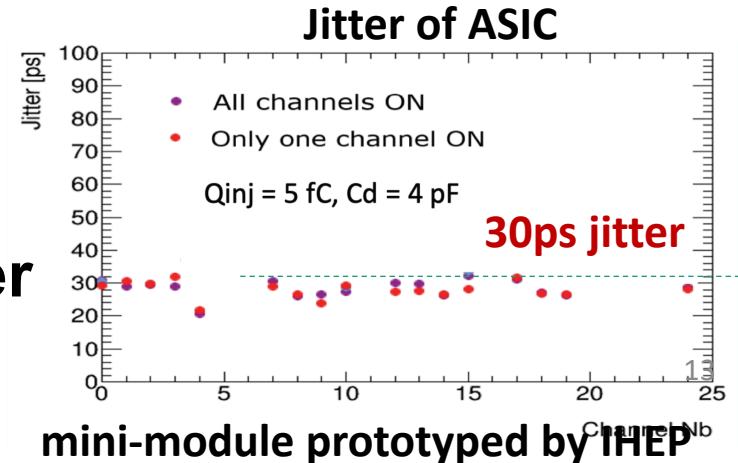
➤ Performance of IHEP modules at test beam

➤ Timing resolution at module level **~40ps**

➤ Major result in HGTD TDR

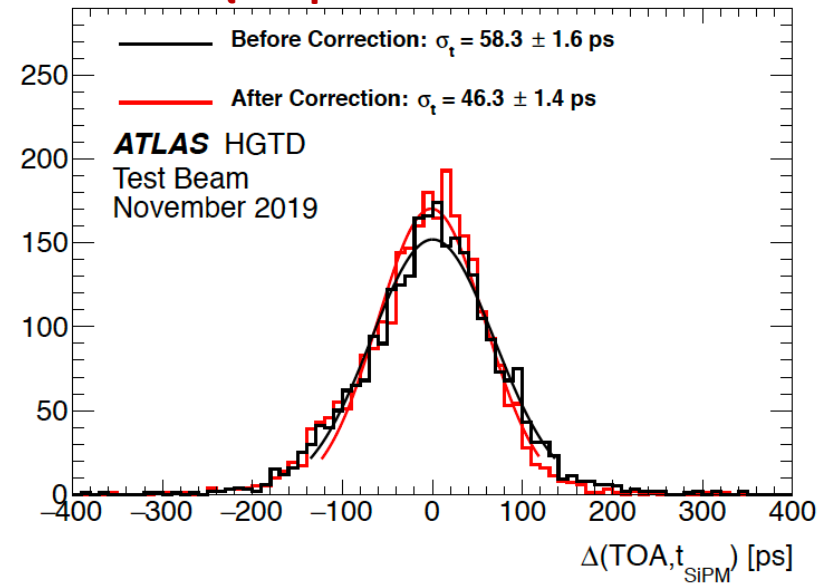
➤ Next step

➤ Improve assembly to reduce jitter



mini-module prototyped by IHEP

$\sigma_t = 46ps$ In beam test



Mini-Module at test beam



HGTD Module R& D

➤ IHEP is playing a leading role in module R& D

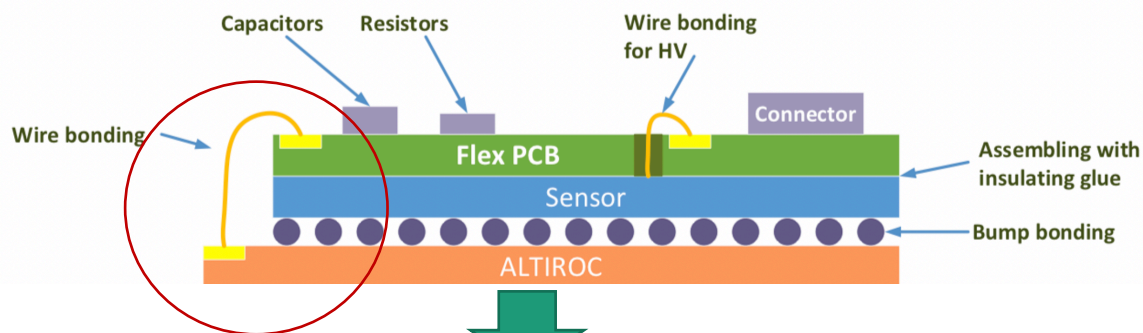
➤ Alternative module design with full bump bonding

➤ Avoid wire bonding, simplify the assembly process, more robust

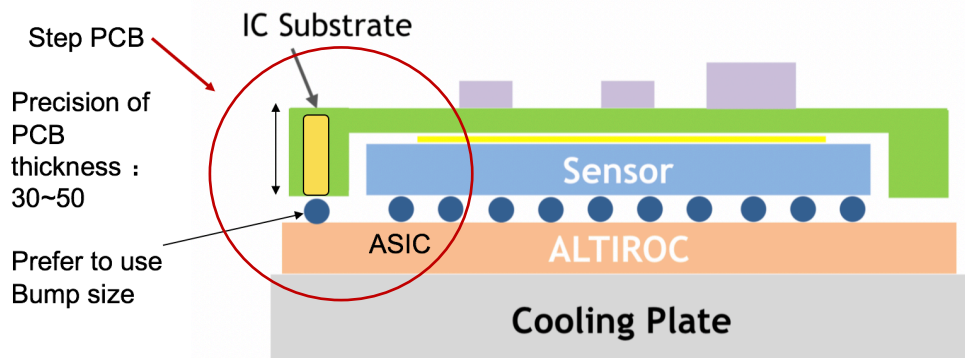
➤ Design module flex and flex cable prototyping

➤ Next step: full size (4 x 2 cm²) module prototyping in 2021

Baseline module design



Alternative module design



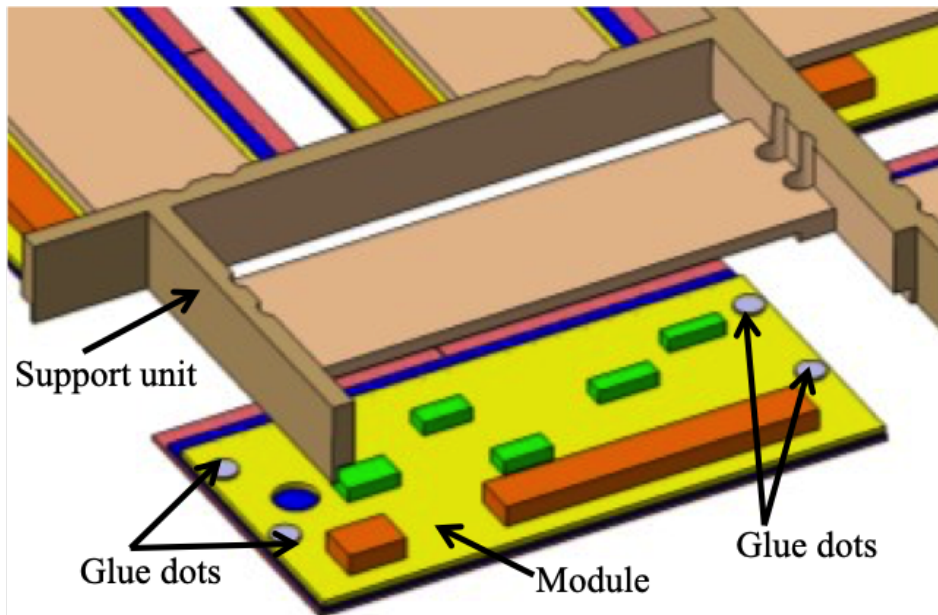
Flex cable prototyping at IHEP



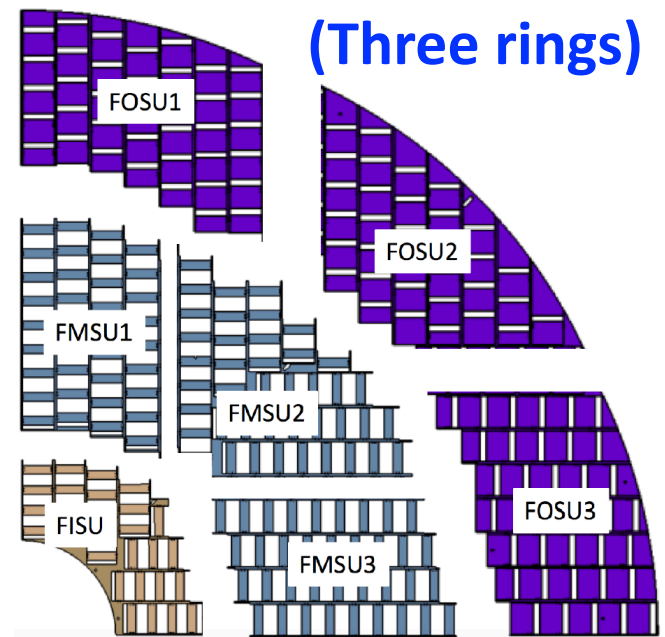
Module and detector units

- Modules will be loaded into carbon fiber support unit
- IHEP is the leading HGTD detector production site
- Six module assembly and loading sites at HGTD
 - IHEP; USTC SINANO (China)
 - IFAE (Spain); LPNHE/IJCLab/IRFU(France);
 - Mainz (Germany);, MASclR (Morocco)

Modules loading on support unit



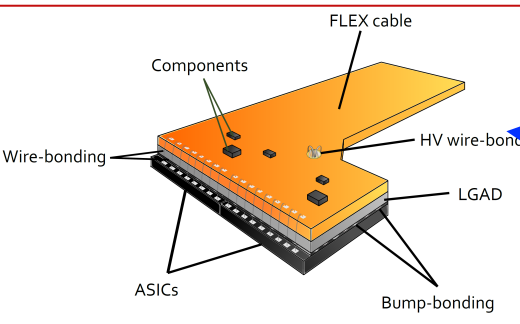
Support unit maps (Three rings)



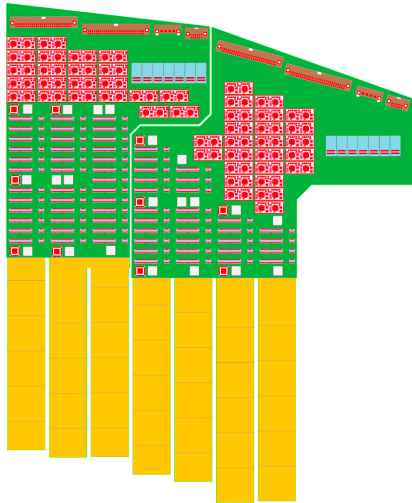
Peripheral Electronics and DAQ

- IHEP/NJU are leading the Peripheral board (PEB) design
 - Proposed rigid board + flexible PCB board design → Became baseline
- IHEP is leading HGTD Data acquisition system (DAQ) group
 - Design DAQ demonstrator, design the data format for up/down link

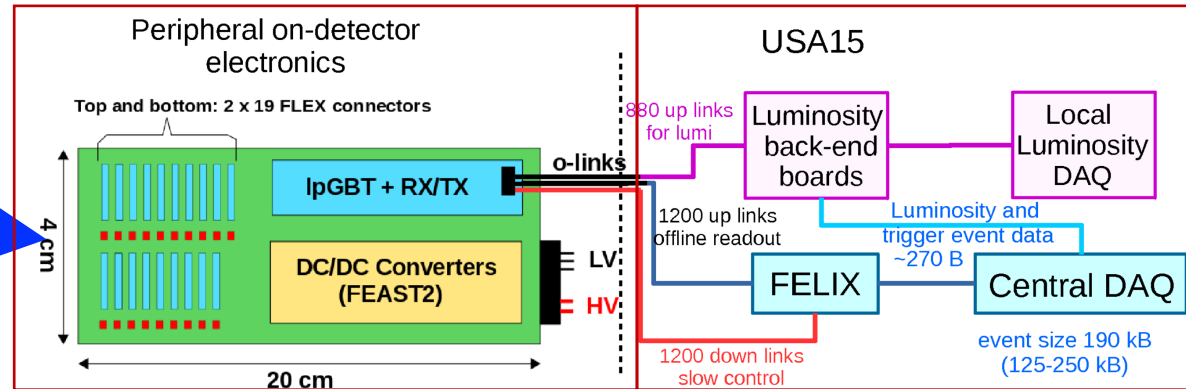
Modules



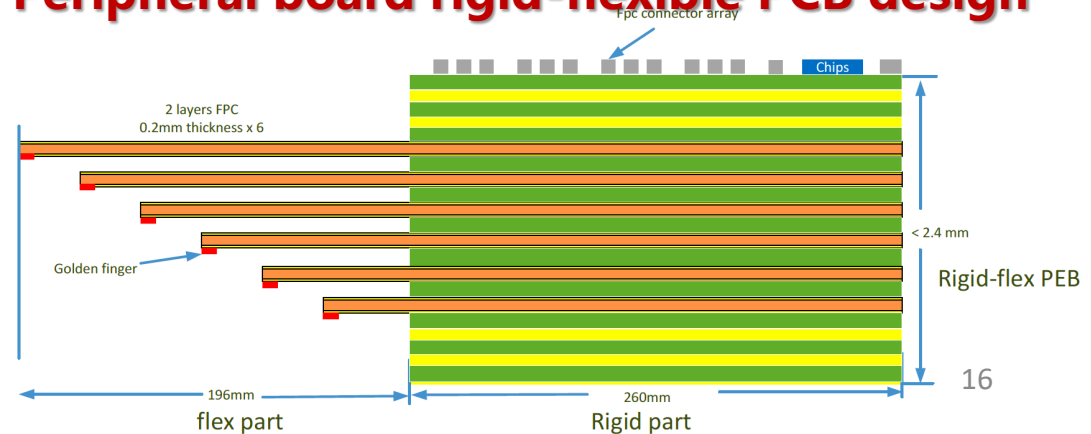
Peripheral



Peripheral Electronics Data acquisition system

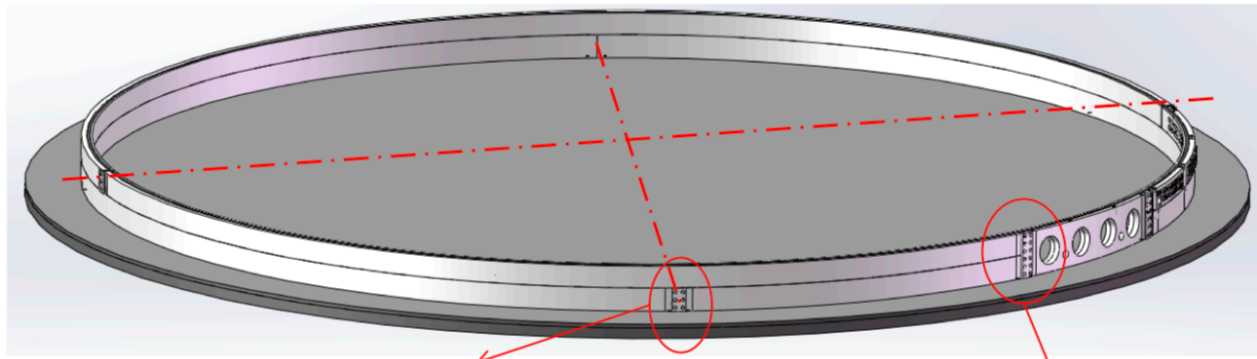


Peripheral board rigid-flexible PCB design



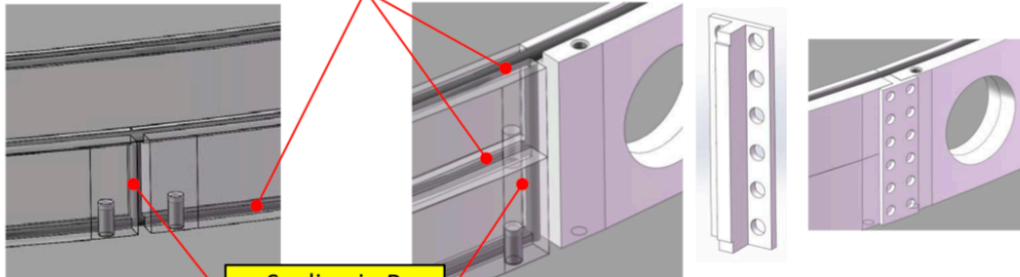
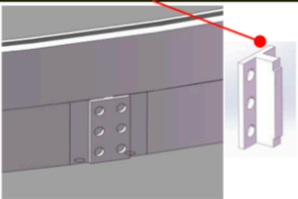
HGTD detector mechanical design

➤ IHEP is leading the mechanical design of HGTD outer ring

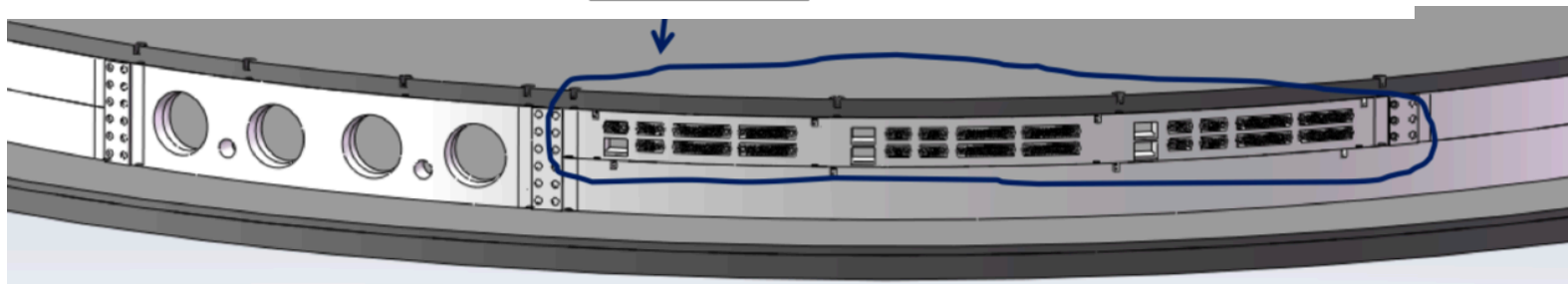


T shaped block: to connect the sections in peripheral direction and press the sealing strip.

Sealing along peripheral direction

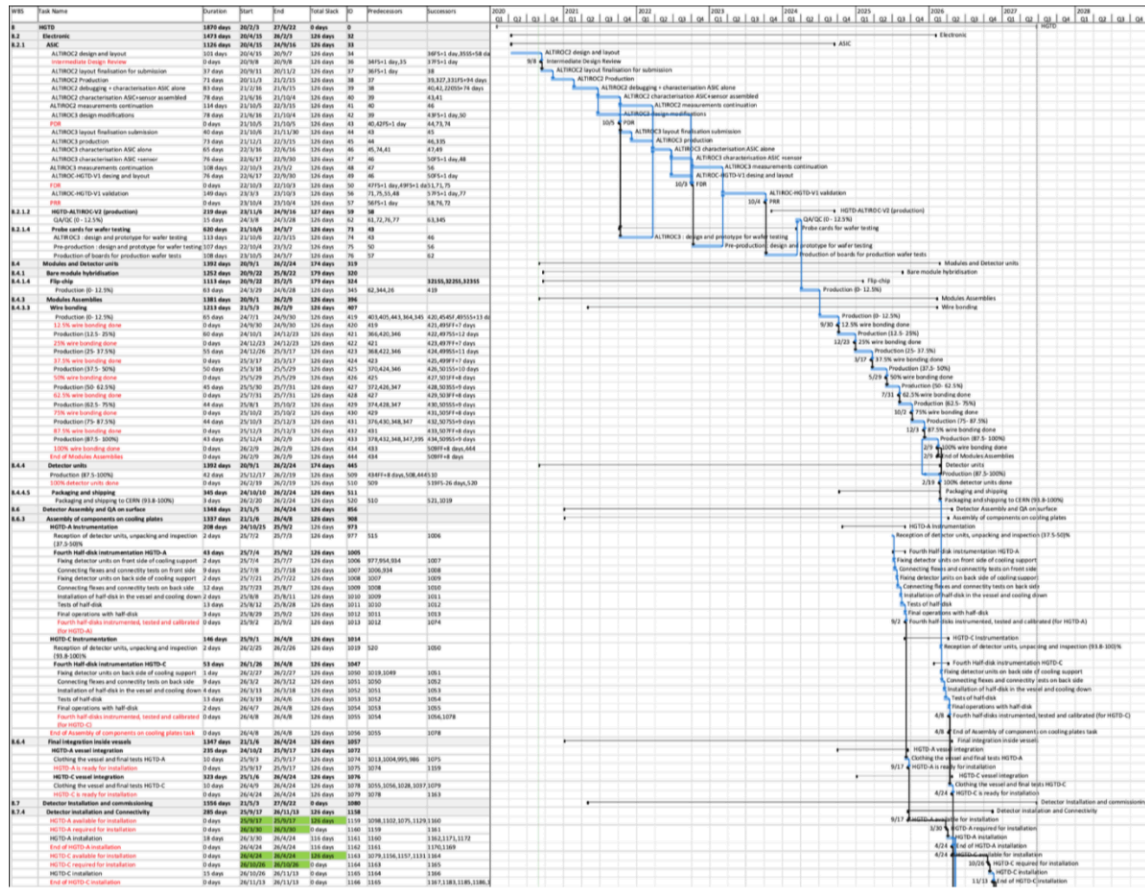


Sealing in R direction



HGTD schedule

- Large effort for UCG review in schedule
- UCG material preparation led by IHEP (Joao Guimaraes Da Costa)
- Full size sensor and module R & D by 2021
- Module and detector units production (2024–2025)
- IHEP is one of the leading production sites
- HGTD installation at CERN by end of 2026.



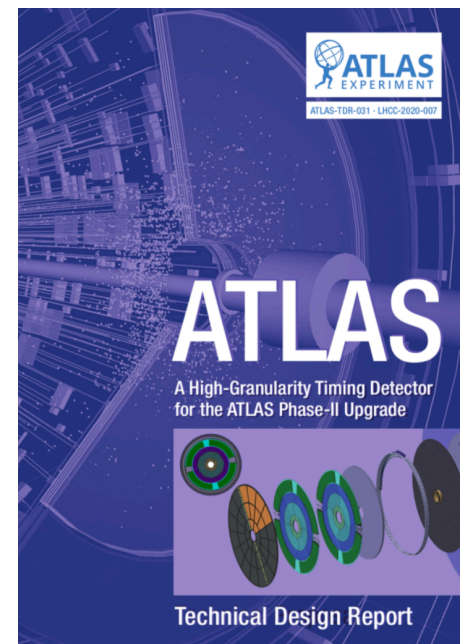
- Critical Path:
- ASIC Production
- ↓
- Module Hybridisation
- ↓
- Module Assembly
- ↓
- Module Loading
- ↓
- Installation at CERN

Includes ATLAS official schedule HGTD installation schedule:
HGTD-A installation: March 2026
HGTD-C installation: October 2026

Summary

- **HGTD Project now fully approved → construction phase**
- **China should play a leading role in the HGTD construction**
- **Ultra-fast sensors and ASIC in HGTD is interesting new tech.**
 - **Fast timing, radiation hard, larger area silicon sensors.**
 - **Interesting for future experiments (Time of flight detector)**
 - **Medical imaging application: Proton CT (proposed in US)**
- **IHEP/NJU Contributions in HGTD**
 - **Design and testing LGAD sensors**
 - **Design of electronics**
 - **Design of modules and flex cables**
 - **Mechanics and Integration**
 - **Management, planning**
 - **TDR editing (Editors in key Chapters)**

HGTD technical design report



IHEP-NDL v3: Irradiation hardness

➤ New IHEP-NDL (v3)

- Active layer thickness from 33 → 50 μm
- Improve charge collection after irradiation

